



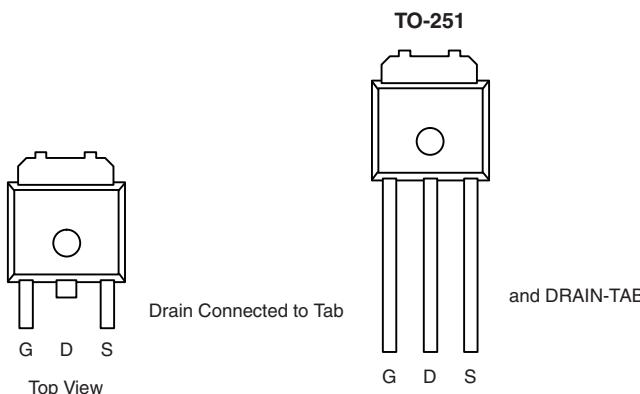
## N-Channel 100-V (D-S), 175 °C MOSFET

## PRODUCT SUMMARY

$V_{DS}$ (V)	$r_{DS(on)}$ ( $\Omega$ )	$I_D$ (A) <sup>a</sup>	$Q_g$ (Typ)
100	0.0185 at $V_{GS} = 10$ V	50	48 nC

## FEATURES

- TrenchFET® Power MOSFET
- 100 %  $R_g$  Tested
- 100 % UIS Tested

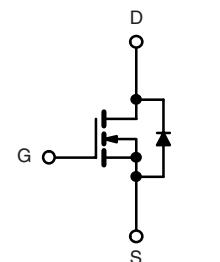


Order Number:  
SUD50N10-18P-E3 (Lead (Pb)-free)

Order Number:  
SUU50N10-18P-E3 (Lead (Pb)-free)

## APPLICATIONS

- Primary Side Switch
- Isolated DC/DC Converter



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS  $T_A = 25$  °C, unless otherwise noted

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	100	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	
Continuous Drain Current ( $T_J = 150$ °C)	$I_D$	50 <sup>a</sup>	
		39	
		8.2 <sup>b</sup>	
		5.8 <sup>b</sup>	
Pulsed Drain Current	$I_{DM}$	100	A
Continuous Source-Drain Diode Current	$I_S$	50 <sup>a</sup>	
		2.0 <sup>b</sup>	
Single Pulse Avalanche Current	$I_{AS}$	45	
Avalanche Energy	$E_{AS}$	101	mJ
Maximum Power Dissipation	$P_D$	136.4	
		68.2	
		3.0 <sup>b</sup>	
		1.5 <sup>b</sup>	
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	- 55 to 175	°C

## THERMAL RESISTANCE RATINGS

Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient <sup>b</sup>	$R_{thJA}$	40	50	°C/W
Maximum Junction-to-Case	$R_{thJC}$	0.85	1.1	

Notes:

a. Package limited.

b. Surface mounted on 1" x 1" FR4 board.

**SUU/SUD50N10-18P**

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**SPECIFICATIONS**  $T_J = 25^\circ\text{C}$ , unless otherwise noted

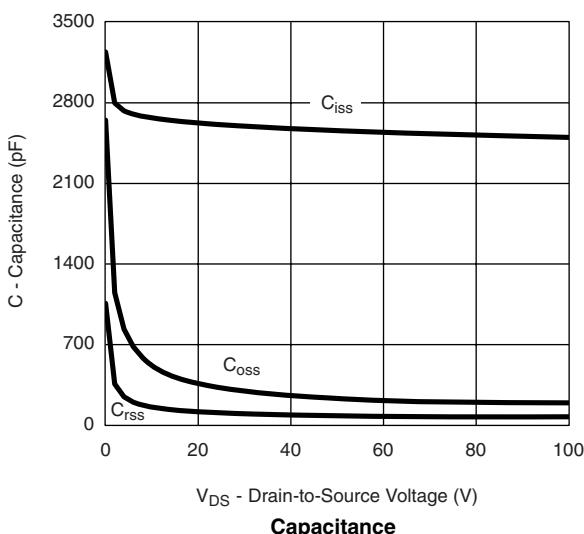
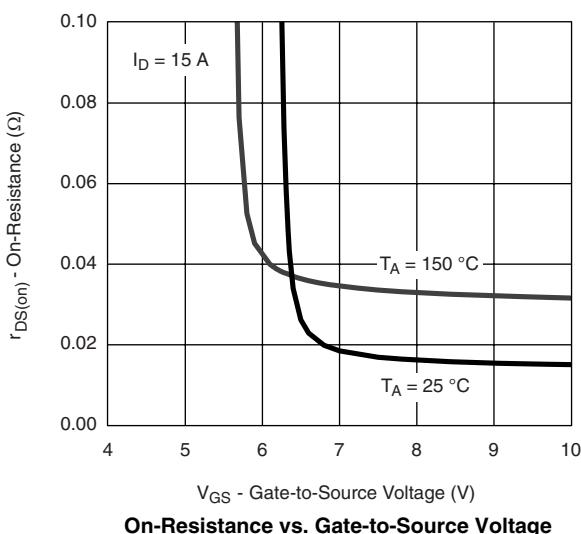
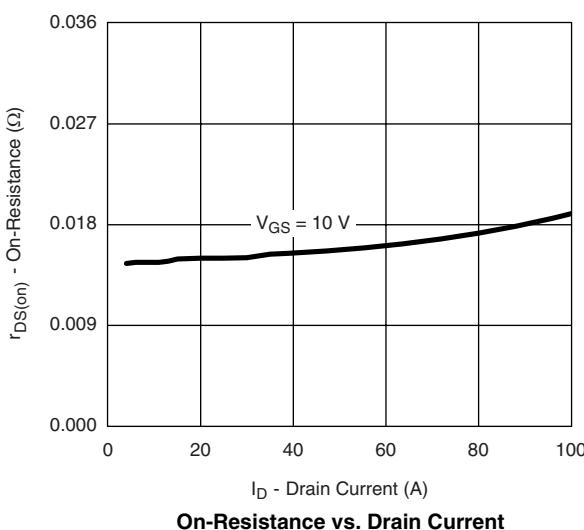
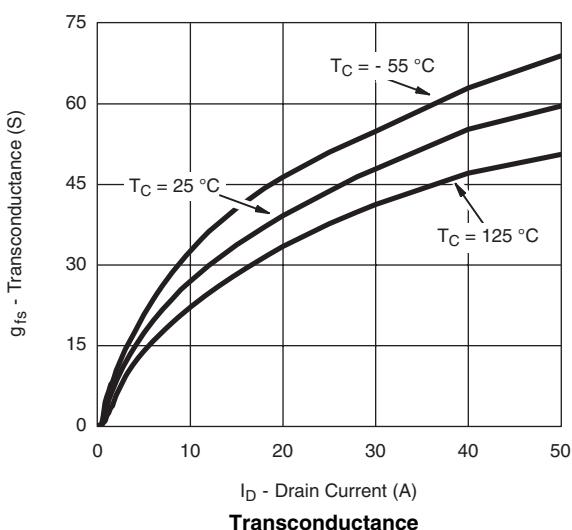
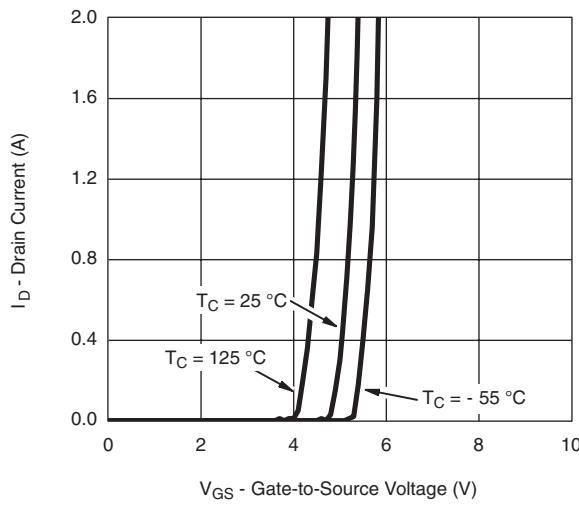
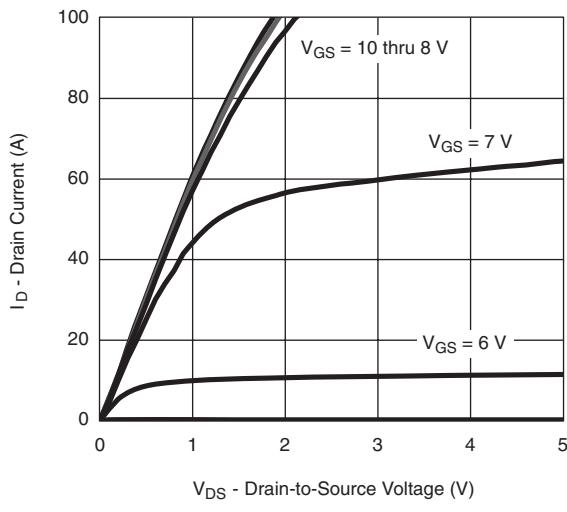
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static</b>						
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			V
$V_{DS}$ Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250 \mu\text{A}$		110		mV/ $^\circ\text{C}$
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$			- 12.5		
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2.5		5	V
Gate-Source Leakage	$I_{GSS}$	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}$			1	$\mu\text{A}$
		$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125^\circ\text{C}$			50	
On-State Drain Current <sup>a</sup>	$I_{D(\text{on})}$	$V_{DS} \geq 5 \text{ V}, V_{GS} = 10 \text{ V}$	50			A
Drain-Source On-State Resistance <sup>a</sup>	$r_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 15 \text{ A}$		0.015	0.0185	$\Omega$
Forward Transconductance <sup>a</sup>	$g_{fs}$	$V_{DS} = 15 \text{ V}, I_D = 15 \text{ A}$		33		S
<b>Dynamic<sup>b</sup></b>						
Input Capacitance	$C_{iss}$	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		2600		pF
Output Capacitance	$C_{oss}$			230		
Reverse Transfer Capacitance	$C_{rss}$			80		
Total Gate Charge	$Q_g$	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 50 \text{ A}$		48	75	nC
Gate-Source Charge	$Q_{gs}$			16		
Gate-Drain Charge	$Q_{gd}$			13		
Gate Resistance	$R_g$	$f = 1 \text{ MHz}$		1.6	2.5	$\Omega$
Turn-On Delay Time	$t_{d(\text{on})}$			12	20	ns
Rise Time	$t_r$	$V_{DD} = 50 \text{ V}, R_L = 1.0 \Omega$ $I_D \geq 50 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		10	20	
Turn-Off Delay Time	$t_{d(\text{off})}$			18	35	
Fall Time	$t_f$			8	15	
<b>Drain-Source Body Diode Characteristics</b>						
Continuous Source-Drain Diode Current	$I_S$	$T_C = 25^\circ\text{C}$ $I_S = 15 \text{ A}$ $I_F = 50 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$			50	A
Pulse Diode Forward Current <sup>a</sup>	$I_{SM}$				100	
Body Diode Voltage	$V_{SD}$			0.85	1.5	V
Body Diode Reverse Recovery Time	$t_{rr}$			80	120	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$			160	240	
Reverse Recovery Fall Time	$t_a$			57		
Reverse Recovery Rise Time	$t_b$			23		

## Notes:

a. Pulse test; pulse width  $\leq 300 \mu\text{s}$ , duty cycle  $\leq 2 \%$ .

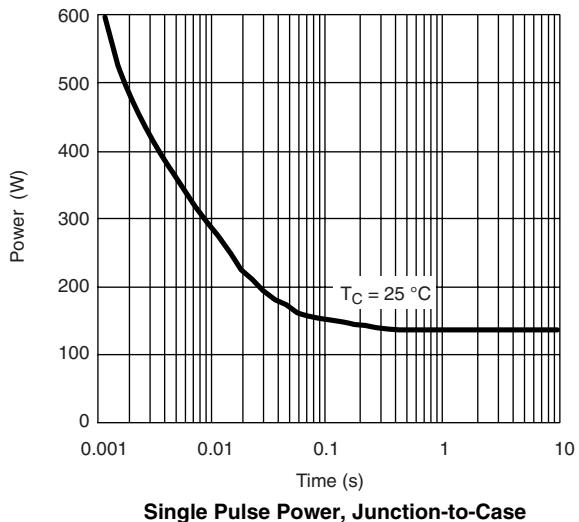
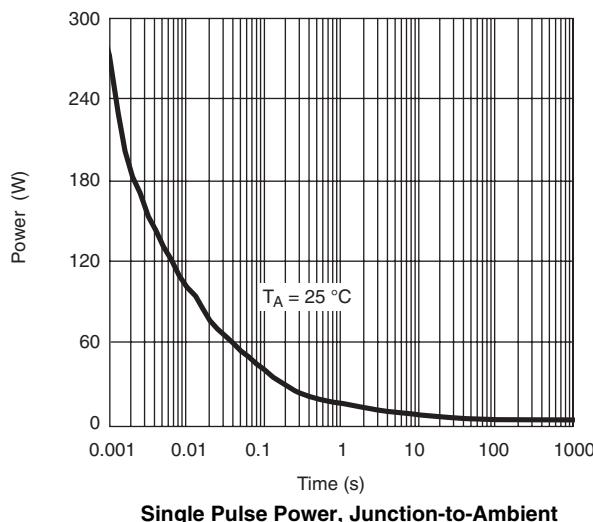
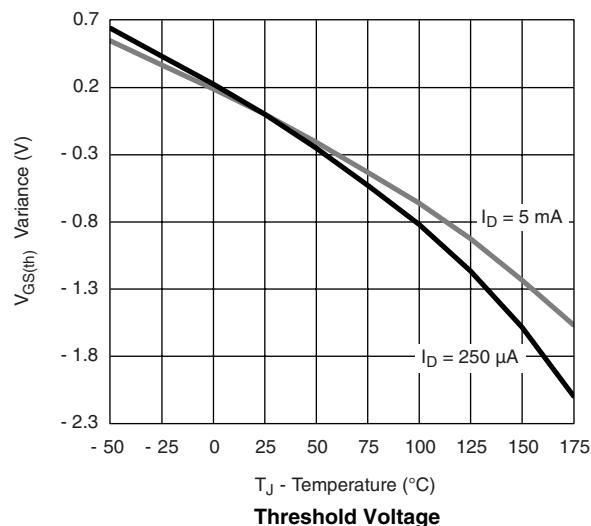
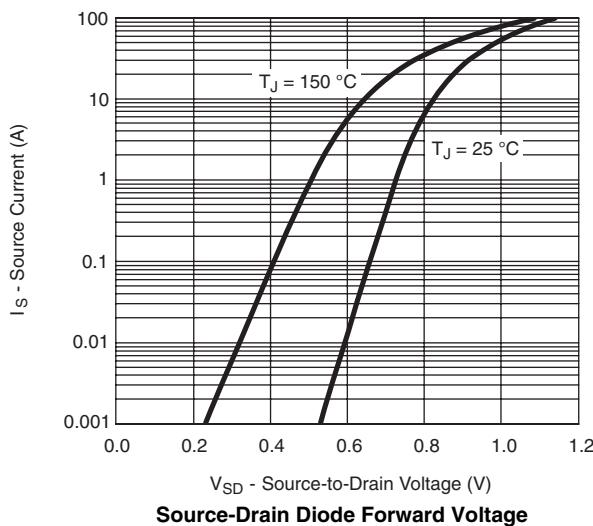
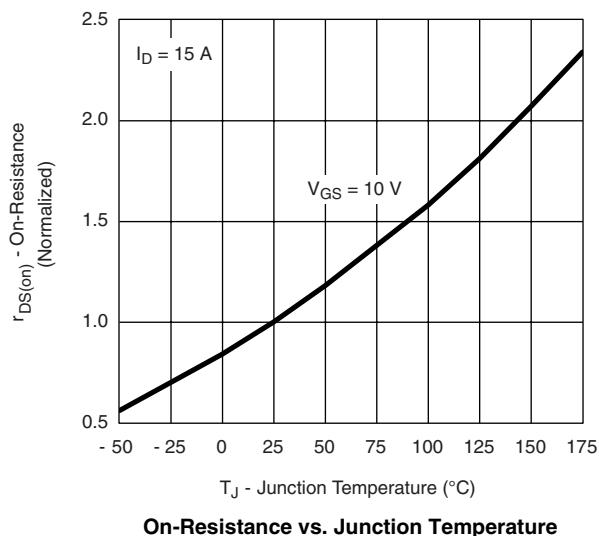
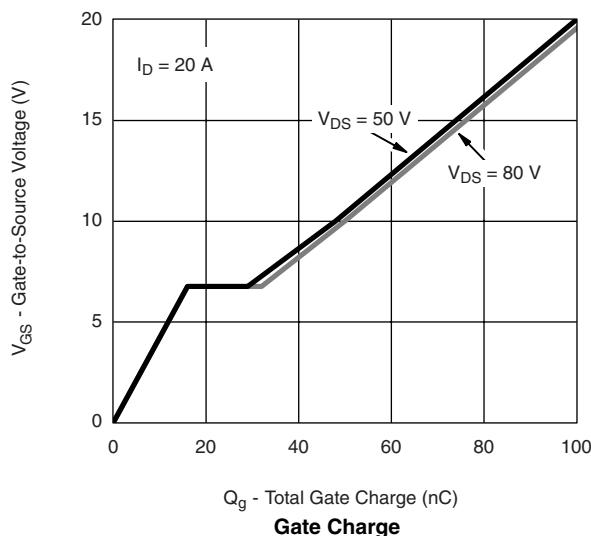
b. Guaranteed by design, not subject to production testing.

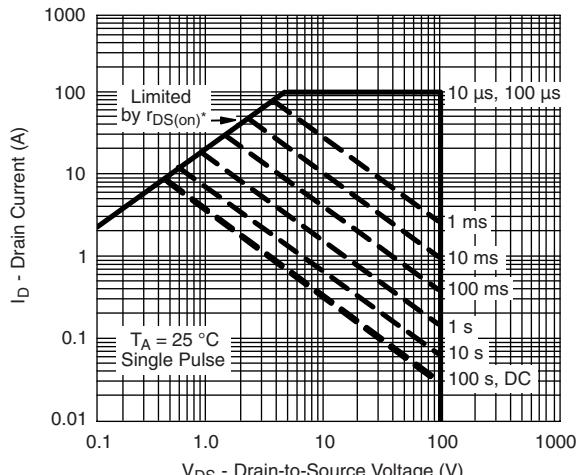
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted


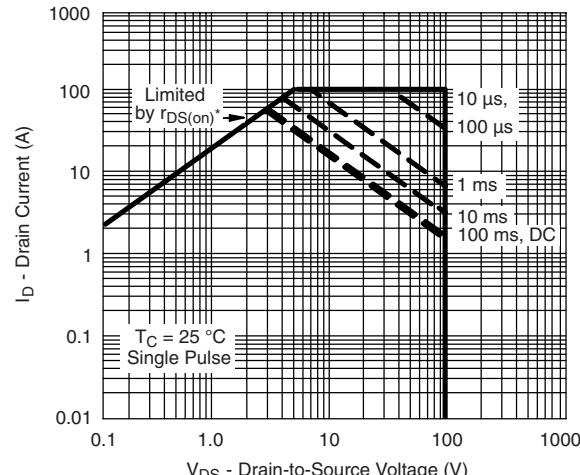
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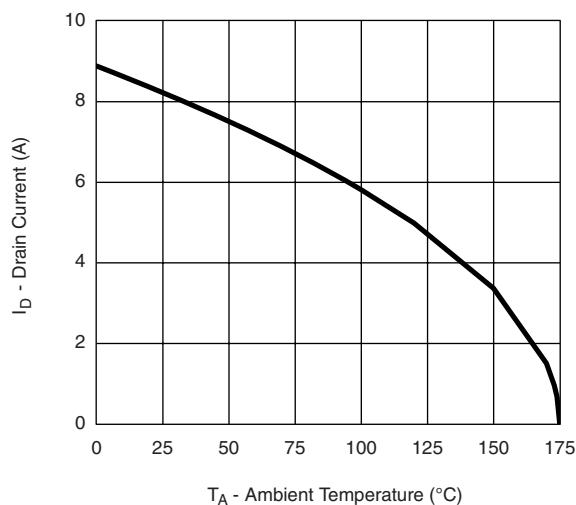
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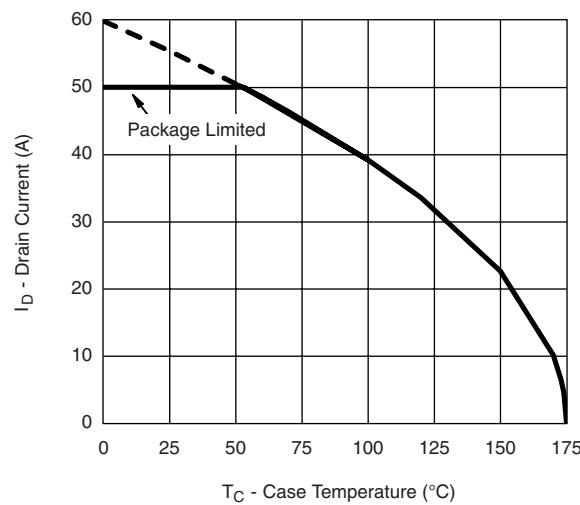
\*  $V_{GS} >$  minimum  $V_{GS}$  at which  $r_{DS(on)}$  is specified  
Safe Operating Area, Junction-to-Ambient



\*  $V_{GS} >$  minimum  $V_{GS}$  at which  $r_{DS(on)}$  is specified  
Safe Operating Area, Junction-to-Case



Current Derating\*\*, Junction-to-Ambient

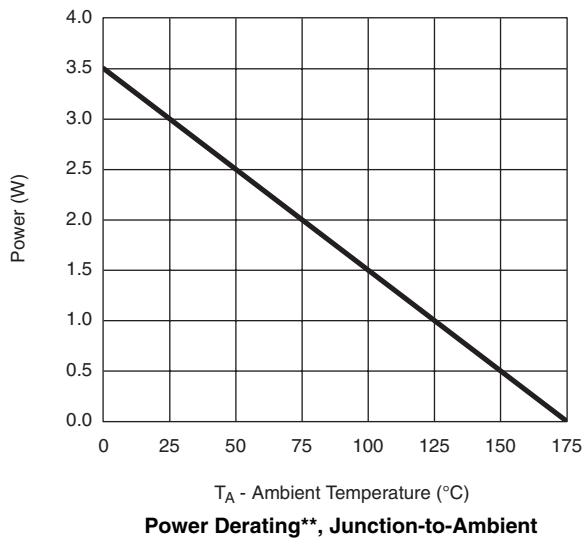


Current Derating\*\*, Junction-to-Case

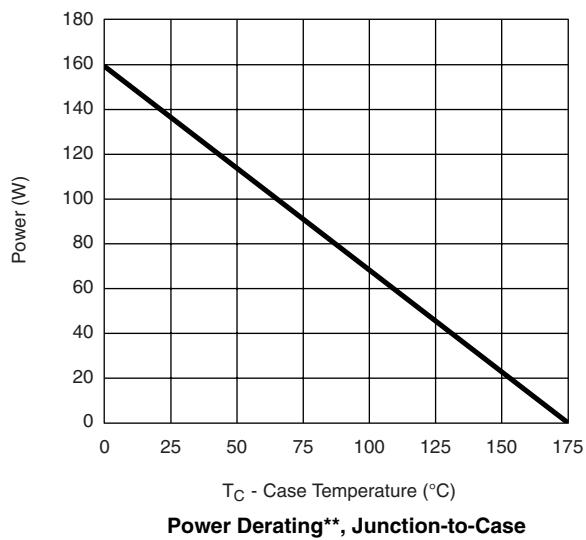
\*\* The power dissipation  $P_D$  is based on  $T_{J(max)} = 175$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

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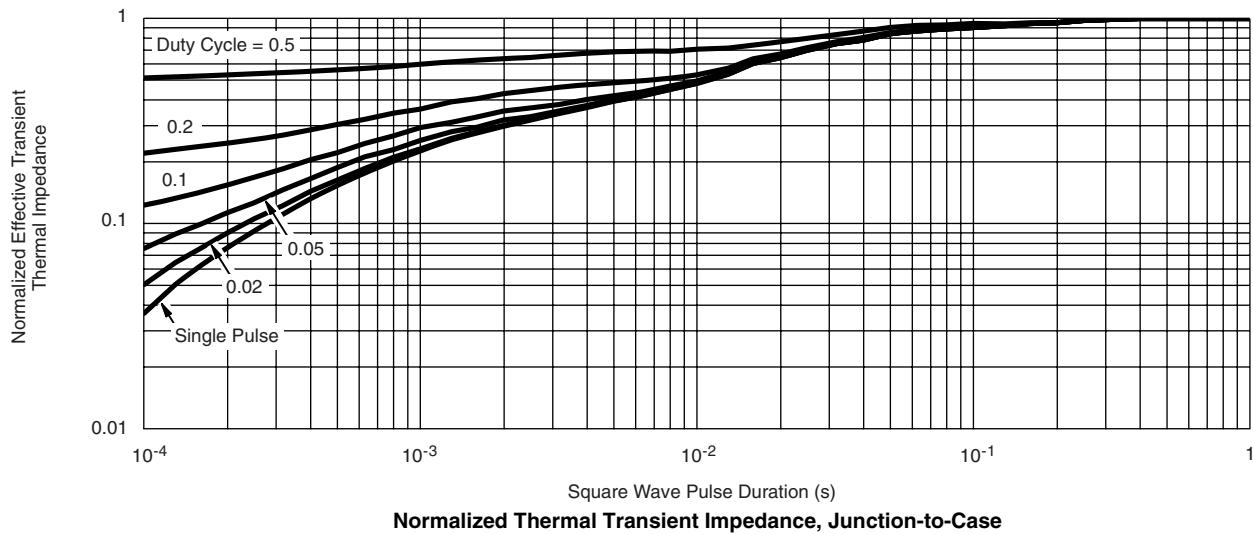
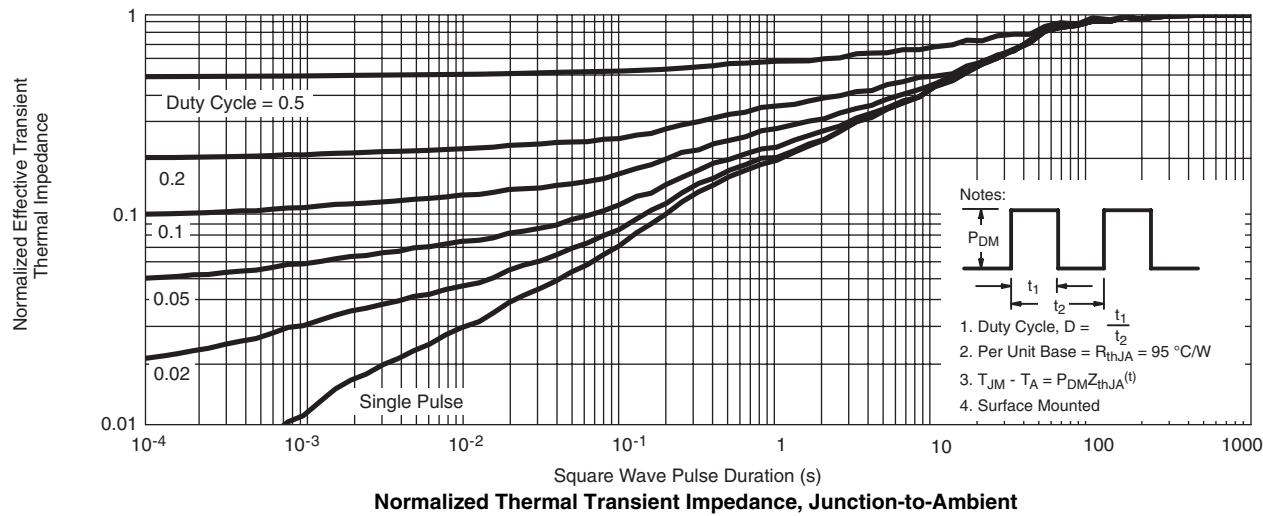
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**Power Derating\*\*, Junction-to-Ambient**



**Power Derating\*\*, Junction-to-Case**

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